Contents

1 **Block diagram and pin description 5**
1.1 Block diagram 5
1.2 Pin description 5

2 **Mechanical and electrical specifications 7**
2.1 Mechanical characteristics 7
2.2 Electrical characteristics 8
2.3 Communication interface characteristics 9
2.3.1 SPI - serial peripheral interface 9
2.3.2 I2C - Inter IC control interface 10
2.4 Absolute maximum ratings 11
2.5 Terminology 12
2.5.1 Sensitivity 12
2.5.2 Zero-g level 12
2.5.3 Self test 12

3 **Functionality 13**
3.1 Sensing element 13
3.2 IC interface 13
3.3 Factory calibration 13

4 **Application hints 14**
4.1 Soldering information 14

5 **Digital interfaces 15**
5.1 I2C serial interface 15
5.1.1 I2C operation 16
5.2 SPI bus interface 17
5.2.1 SPI read 18
5.2.2 SPI write 19
5.2.3 SPI read in 3-wires mode 20

6 **Register mapping 21**

7 Register description 22
7.1 CTRL_REG1 (20h) 22
7.2 CTRL_REG2 (21h) 23
7.3 CTRL_REG3 [Interrupt CTRL register] (22h) 23
7.4 STATUS_REG (27h) 24
7.5 OUT_X (29h) 25
7.6 OUT_Y (2Bh) 25
7.7 OUT_Z (2Dh) 25
7.8 FF_WU_CFG (30h) 25
7.9 FF_WU_SRC (31h) 26
7.10 FF_WU_THS (32h) 27
7.11 FF_WU_DURATION (33h) 27
8 Package information 28
9 Revision history 29

List of tables

Table 1. Device summary . . . 1
Table 2. Pin description . . . 7
Table 3. Mechanical characteristics @ Vdd=2.5V . . . 8
Table 4. Electrical characteristics @ Vdd=2.5V . . . 9
Table 5. SPI slave timing values . . . 10
Table 6. I2C slave timing values . . . 11
Table 7. Absolute maximum ratings . . . 12
Table 8. Serial interface pin description . . . 16
Table 9. Serial interface pin description . . . 16
Table 10. Transfer when Master is writing one byte to slave . . . 17
Table 11. Transfer when Master is writing multiple bytes to slave: . . . 17
Table 12. Transfer when Master is receiving (reading) one byte of data from slave: . . . 17
Table 13. Transfer when Master is receiving (reading) one byte of data from slave . . . 17
Table 14. Transfer when Master is receiving (reading) multiple bytes of data from slave . . . 18
Table 15. Register address map . . . 22
Table 16. CTRL_REG1 (20h) register . . . 23
Table 17. CTRL_REG1 (20h) register description . . . 23
Table 18. CTRL_REG2 (21h) register . . . 24
Table 19. CTRL_REG2 (21h) register description . . . 24
Table 20. CTRL_REG3 (22h) register . . . 24
Table 21. CTRL_REG3 (22h) register description . . . 24
Table 22. Data signal on INT pad control bits . . . 25
Table 23. STATUS_REG (27h) register . . . 25
Table 24. STATUS_REG (27h) register description . . . 25
Table 25. OUT_X (29h) register . . . 26
Table 26. OUT_Y (2Bh) register . . . 26
Table 27. OUT_Z (2Dh) register . . . 26
Table 28. FF_WU_CFG (30h) register . . . 26
Table 29. FF_WU_CFG (30h) register description . . . 26
Table 30. FF_WU_SRC (31h) register . . . 27
Table 31. FF_WU_SRC (31h) register description . . . 27
Table 32. FF_WU_THS (32h) register . . . 28
Table 33. FF_WU_THS (32h) register description . . . 28
Table 34. FF_WU_DURATION (33h) register . . . 28
Table 35. FF_WU_DURATION (33h) register description . . . 28
Table 36. Document revision history . . . 30

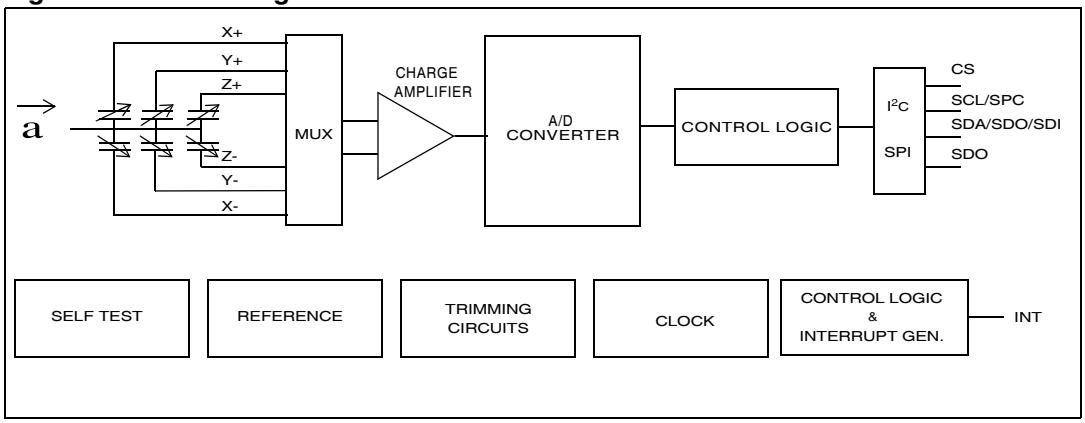
List of figures

Figure 1. Block diagram . . . 6
Figure 2. Pin connection . . . 6
Figure 3. SPI slave timing diagram . . . 10
Figure 4. I2C slave timing diagram . . . 11
Figure 5. LIS33DE electrical connection . . . 15
Figure 6. Read and write protocol . . . 18
Figure 7. SPI read protocol . . . 19
Figure 8. Multiple bytes SPI read protocol (2 bytes example) . . . 20
Figure 9. SPI write protocol . . . 20
Figure 10. Multiple bytes SPI write protocol (2 bytes example) . . . 20
Figure 11. SPI read protocol in 3-wires mode . . . 21
Figure 12. LGA 16: mechanical data and package dimensions . . . 29

1 Block diagram and pin description

1.1 Block diagram

Figure 1. Block diagram



1.2 Pin description

Figure 2. Pin connection

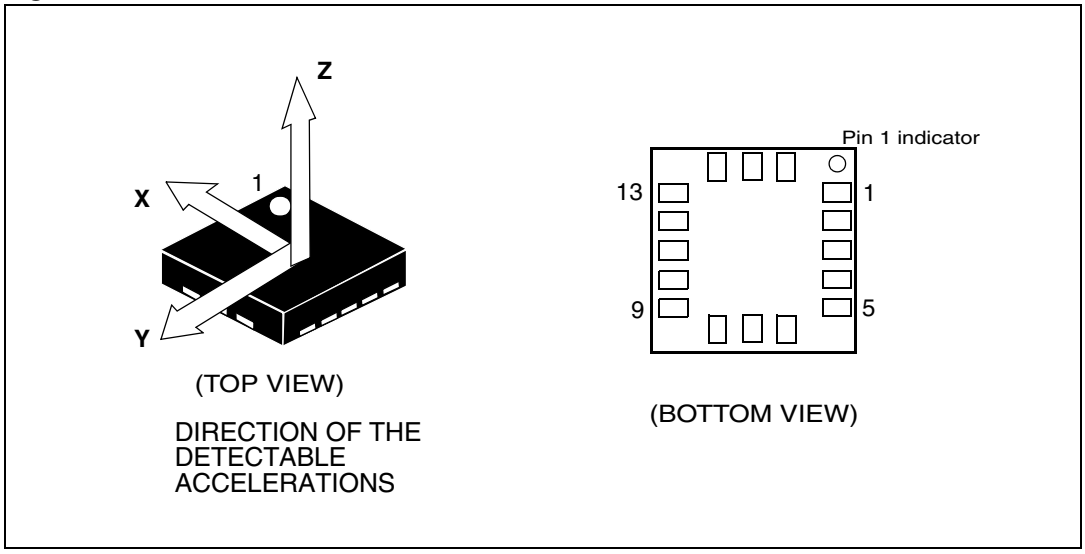


Table 2. Pin description

Pin#	Name	Function
1	Vdd_IO	Power supply for I/O pins
2	NC	Not connected
3	NC	Not connected
4	SCL SPC	I^2C serial clock (SCL) SPI serial port clock (SPC)
5	GND	0 V supply
6	SDA SDI SDO	I^2C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO)
7	SDO	SPI serial data output I^2C less significant bit of the device address
8	CS	SPI enable I^2C/SPI mode selection (1: I^2C mode; 0: SPI enabled)
9	Reserved	Leave unconnected
10	Reserved	Connect to Gnd
11	INT	Inertial interrupt
12	GND	0 V supply
13	GND	0 V supply
14	Vdd	Power supply
15	Reserved	Connect to Vdd
16	GND	0V supply

2 Mechanical and electrical specifications

2.1 Mechanical characteristics

T = 25°C unless otherwise noted

Table 3. Mechanical characteristics @ Vdd=2.5V (1)

Symbol	Parameter	Test conditions	Min.	Typ.(2)	Max.	Unit
FS	Measurement range	FS bit set to 0(3)	±2.0	±2.3		g
		FS bit set to 1		±9.2		
Dres	Device resolution	FS bit set to 0		72		mg
So	Sensitivity	FS bit set to 0	15	18	21	mg/digit
		FS bit set to 1	61	72	83	
TCSO	Sensitivity change vs temperature	FS bit set to 0		±0.01		%/°C
TyOff	Typical zero-g level offset accuracy(4)	FS bit set to 0		±60		mg
		FS bit set to 1		±80		mg
TCOff	Zero-g level change vs temperature	Max delta from 25°C		±0.5		mg/°C
Vst	Self test output change(5),(6),(7)	FS bit set to 0 STP bit used X axis	-3	-19	-32	LSb
		FS bit set to 0 STP bit used Y axis	3	19	32	LSb
		FS bit set to 0 STP bit used Z axis	-3	-19	-32	LSb
BW	System bandwidth(8)			ODR/2		Hz
Top	Operating temperature range		-40		+85	°C
Wh	Product weight			20		mgram

1. The product is factory calibrated at 2.5 V. The device can be used from 2.16 V to 3.6 V.
2. Typical specifications are not guaranteed.
3. Verified by wafer level test and measurement of initial offset and sensitivity.
4. Typical zero-g level offset value after MSL3 preconditioning.
5. If STM bit is used, values change in sign for all axes.
6. Self Test output changes with the power supply. “Self Test Output Change” is defined as $OUTPUT[LSb]_{(Self\text{-}test\ bit\ on\ ctrl\_reg1=1)}$ $-OUTPUT[LSb]_{(Self\text{-}test\ bit\ on\ ctrl\_reg1=0)}$. 1LSb=4.6g/256 at 8bit representation, ±2.3g full-scale.
7. Output data reach 99% of final value after 3/ODR when enabling self-test mode due to device filtering.
8. ODR is Output Data Rate. Refer to *Table 4* for specifications.

2.2 Electrical characteristics

T = 25°C unless otherwise noted

Table 4. Electrical characteristics @ Vdd=2.5V (1)

Symbol	Parameter	Test conditions	Min.	Typ.(2)	Max.	Unit
Vdd	Supply voltage		2.16	2.5	3.6	V
Vdd_IO	I/O pins supply voltage(3)		1.71		Vdd+0.1	V
Idd	Supply current	T = 25°C, ODR=100 Hz		0.3	0.45	mA
IddPdn	Current consumption in power-down mode	T = 25°C		1	5	µA
VIH	Digital high level Input voltage		0.8*Vdd_IO			V
VIL	Digital low level input voltage				0.2*Vdd_IO	V
VOH	High level output voltage		0.9*Vdd_IO			V
VOL	Low level output voltage				0.1*Vdd_IO	V
ODR	Output data rate	DR=0		100		Hz
		DR=1		400		
BW	System bandwidth(4)			ODR/2		Hz
Ton	Turn-on time(5)			3/ODR		s
Top	Operating temperature range		-40		+85	°C

1. The product is factory calibrated at 2.5V. The device can be used from 2.16V to 3.6V.
2. Typical specification are not guaranteed.
3. It is possible to remove Vdd maintaining Vdd_IO without blocking the communication busses, in this condition the measurement chain is powered off.
4. Filter cut-off frequency.
5. Time to obtain valid data after exiting Power-Down mode.

2.3 Communication interface characteristics

2.3.1 SPI - serial peripheral interface

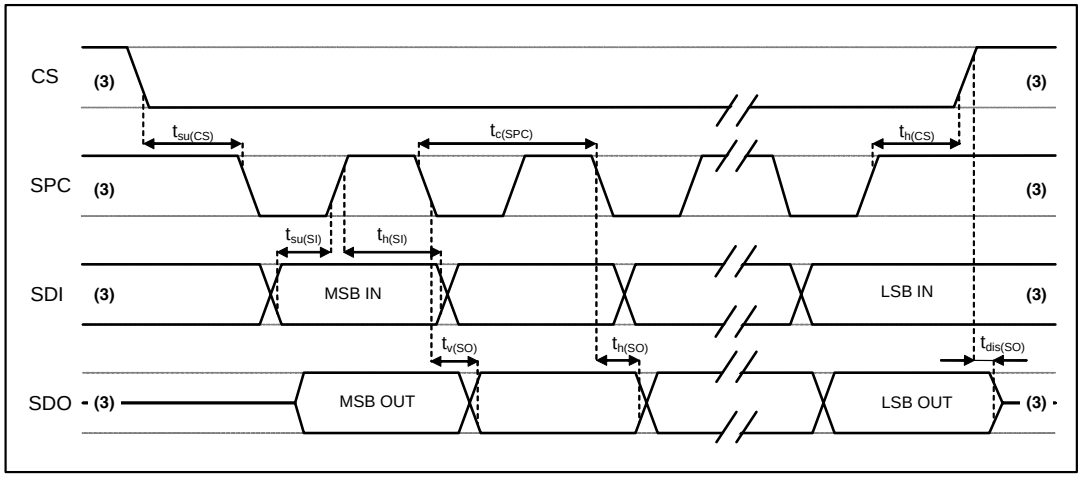
Subject to general operating conditions for Vdd and top.

Table 5. SPI slave timing values

Symbol	Parameter	Value(1)		Unit
		Min	Max	
tc(SPC)	SPI clock cycle	100		ns
fc(SPC)	SPI clock frequency		10	MHz
tsu(CS)	CS setup time	5		ns
th(CS)	CS hold time	8		
tsu(SI)	SDI input setup time	5		
th(SI)	SDI input hold time	15		
tv(SO)	SDO valid output time		50	
th(SO)	SDO output hold time	6		
tdis(SO)	SDO output disable time		50	

1. Values are guaranteed at 10 MHz clock frequency for SPI with both 4 and 3 wires, based on characterization results, not tested in production

Figure 3. SPI slave timing diagram (a)



3. When no communication is on-going, data on CS, SPC, SDI and SDO are driven by internal pull-up resistors

a. Measurement points are done at 0.2·Vdd_IO and 0.8·Vdd_IO, for both Input and Output port

2.3.2 I²C - Inter IC control interface

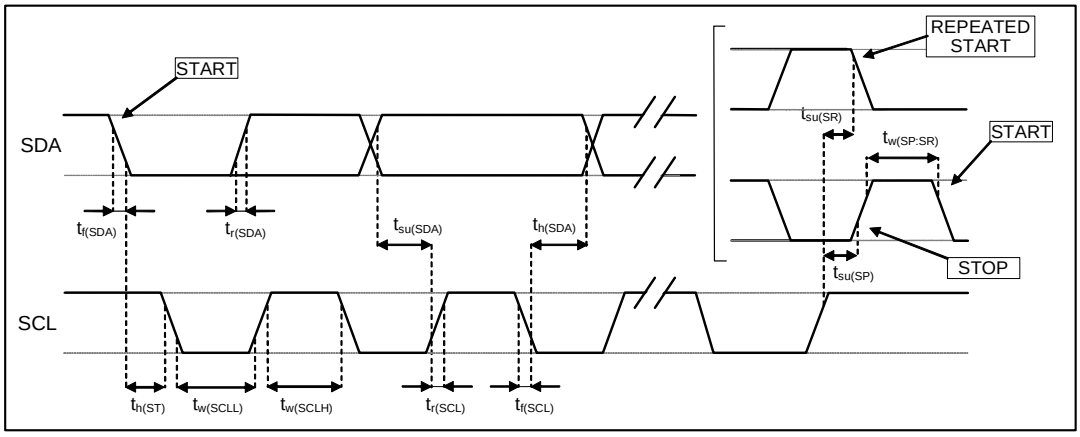
Subject to general operating conditions for Vdd and top.

Table 6. I²C slave timing values

Symbol	Parameter	I²C standard mode(1)		I²C fast mode (1)		Unit
		Min.	Max.	Min.	Max.	
$f_{(SCL)}$	SCL clock frequency	0	100	0	400	KHz
$t_{w(SCLL)}$	SCL clock low time	4.7		1.3		µs
$t_{w(SCLH)}$	SCL clock high time	4.0		0.6		
$t_{su(SDA)}$	SDA setup time	250		100		ns
$t_{h(SDA)}$	SDA data hold time	0.01	3.45	0.01	0.9	µs
$t_{r(SDA)}$ $t_{r(SCL)}$	SDA and SCL rise time		1000	$20 + 0.1C_b$ (2)	300	ns
$t_{f(SDA)}$ $t_{f(SCL)}$	SDA and SCL fall time		300	$20 + 0.1C_b$ (2)	300	
$t_{h(ST)}$	START condition hold time	4		0.6		µs
$t_{su(SR)}$	Repeated START condition setup time	4.7		0.6		
$t_{su(SP)}$	STOP condition setup time	4		0.6		
$t_{w(SP:SR)}$	Bus free time between STOP and START condition	4.7		1.3		

1. Data based on standard I²C protocol requirement, not tested in production
2. Cb = total capacitance of one bus line, in pF

Figure 4. I²C slave timing diagram (b)



b. Measurement points are done at 0.2·Vdd_IO and 0.8·Vdd_IO, for both ports

2.4 Absolute maximum ratings

Stresses above those listed as “Absolute maximum ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 7. Absolute maximum ratings

Symbol	Ratings	Maximum value	Unit
Vdd	Supply voltage	-0.3 to 6	V
Vdd_IO	I/O pins supply voltage	-0.3 to 6	V
Vin	Input voltage on any control pin (CS, SCL/SPC, SDA/SDI/SDO)	-0.3 to Vdd_IO +0.3	V
A_{POW}	Acceleration (any axis, powered, Vdd=2.5V)	3000g for 0.5 ms	
		10000g for 0.1 ms	
A_{UNP}	Acceleration (any axis, unpowered)	3000g for 0.5 ms	
		10000g for 0.1 ms	
T_{OP}	Operating temperature range	-40 to +85	°C
T_{STG}	Storage temperature range	-40 to +125	°C
ESD	Electrostatic discharge protection	0 - 2 (HBM)	KV

Note: Supply voltage on any pin should never exceed 6.0 V

This is a Mechanical Shock sensitive device, improper handling can cause permanent damages to the part

This is an ESD sensitive device, improper handling can cause permanent damages to the part

2.5 Terminology

2.5.1 Sensitivity

Sensitivity describes the gain of the sensor and can be determined e.g. by applying 1g acceleration to it. As the sensor can measure DC accelerations this can be done easily by pointing the axis of interest towards the center of the earth, noting the output value, rotating the sensor by 180 degrees (pointing to the sky) and noting the output value again. By doing so, ±1g acceleration is applied to the sensor. Subtracting the larger output value from the smaller one and dividing the result by 2, leads to the actual sensitivity of the sensor. This value changes very little over temperature and also time. The Sensitivity tolerance describes the range of sensitivities of a large population of sensors.

2.5.2 Zero-g level

Zero-g level Offset (TyOff) describes the deviation of an actual output signal from the ideal output signal if no acceleration is present. A sensor in a steady state on a horizontal surface measure 0g in X axis and 0g in Y axis whereas the Z axis measure 1g. The output is ideally in the middle of the dynamic range of the sensor (content of OUT registers 00h, data expressed as 2's complement number). A deviation from ideal value in this case is called Zero-g offset. Offset is to some extent a result of stress to MEMS sensor and therefore the offset can slightly change after mounting the sensor onto a printed circuit board or exposing it to extensive mechanical stress. Offset changes little over temperature, see "Zero-g level change vs. temperature". The Zero-g level tolerance (TyOff) describes the Standard Deviation of the range of Zero-g levels of a population of sensors.

2.5.3 Self test

Self Test allows to check the sensor functionality without moving it. The Self Test function is off when the self-test bit of CTRL_REG1 (control register 1) is programmed to '0'. When the self-test bit of CTRL_REG1 is programmed to '1' an actuation force is applied to the sensor, simulating a definite input acceleration. In this case the sensor outputs exhibit a change in their DC levels which are related to the selected full scale through the device sensitivity. When self test is activated, the device output level is given by the algebraic sum of the signals produced by the acceleration acting on the sensor and by the electrostatic test-force. If the output signals change within the amplitude specified inside *Table 3*, then the sensor is working properly and the parameters of the interface chip are within the defined specifications.

3 Functionality

The LIS33DE is an ultracompact, low-power, digital output 3-axis linear accelerometer packaged in a LGA package. The complete device includes a sensing element and an IC interface able to take the information from the sensing element and to provide a signal to the external world through an I^2C/SPI serial interface.

3.1 Sensing element

A proprietary process is used to create a surface micro-machined accelerometer. The technology allows to carry out suspended silicon structures which are attached to the substrate in a few points called anchors and are free to move in the direction of the sensed acceleration. To be compatible with the traditional packaging techniques a cap is placed on top of the sensing element to avoid blocking the moving parts during the moulding phase of the plastic encapsulation.

When an acceleration is applied to the sensor the proof mass displaces from its nominal position, causing an imbalance in the capacitive half-bridge. This imbalance is measured using charge integration in response to a voltage pulse applied to the capacitor.

At steady state the nominal value of the capacitors are few pF and when an acceleration is applied the maximum variation of the capacitive load is in fF range.

3.2 IC interface

The complete measurement chain is composed by a low-noise capacitive amplifier which converts the capacitive unbalancing of the MEMS sensor into an analog voltage that is finally available to the user by analog-to-digital converters.

The acceleration data may be accessed through an I^2C/SPI interface thus making the device particularly suitable for direct interfacing with a microcontroller.

The LIS33DE features a data-ready signal (RDY) which indicates when a new set of measured acceleration data is available thus simplifying data synchronization in the digital system that uses the device.

The LIS33DE may also be configured to generate an inertial Wake-Up and Free-Fall interrupt signal accordingly to a programmed acceleration event along the enabled axes.

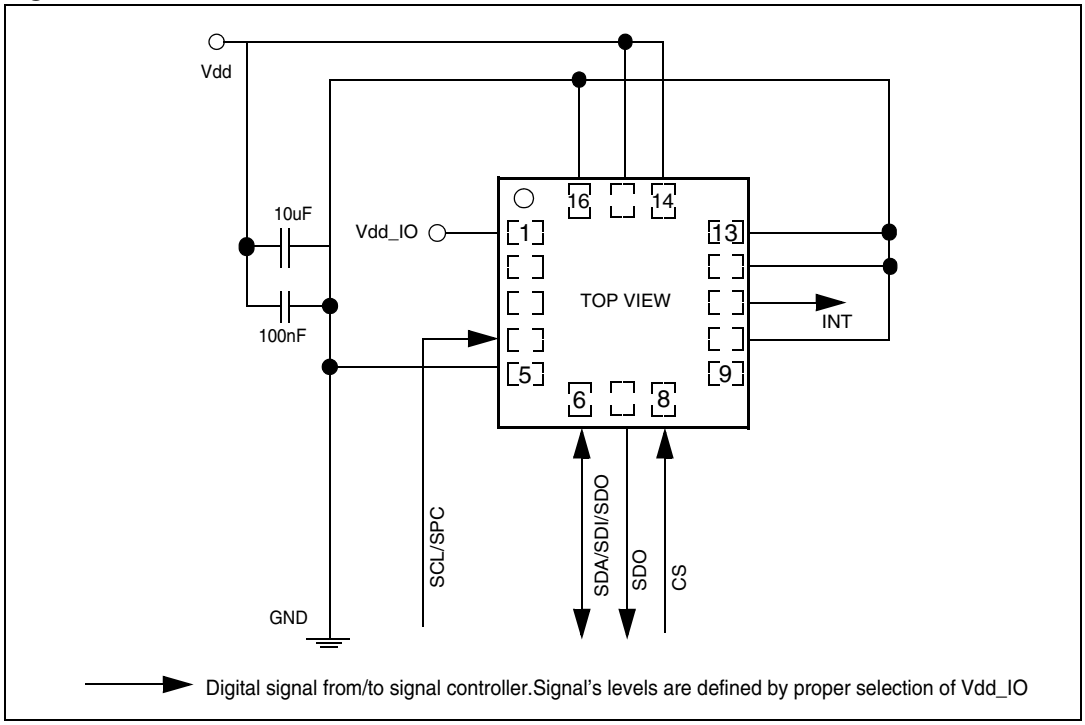
3.3 Factory calibration

The IC interface is factory calibrated for sensitivity (So) and Zero-g level (TyOff).

The trimming values are stored inside the device in a non volatile memory. Any time the device is turned on, the trimming parameters are downloaded into the registers to be used during the normal operation. This allows to use the device without further calibration.

4 Application hints

Figure 5. LIS33DE electrical connection



The device core is supplied through Vdd line while the I/O pads are supplied through Vdd_IO line. Power supply decoupling capacitors (100 nF ceramic, 10 µF Al) should be placed as near as possible to the pin 14 of the device (common design practice).

All the voltage and ground supplies must be present at the same time to have proper behavior of the IC (refer to *Figure 5*). It is possible to remove Vdd maintaining Vdd_IO without blocking the communication bus, in this condition the measurement chain is powered off.

The functionality of the device and the measured acceleration data is selectable and accessible through the I^2C/SPI interface.When using the I^2C, CS must be tied high.

The functions, the threshold and the timing of the interrupt pin (INT) can be completely programmed by the user through the I^2C/SPI interface.

4.1 Soldering information

The LGA package is compliant with the ECOPACK®, RoHS and "Green" standard.
It is qualified for soldering heat resistance according to JEDEC J-STD-020C.

Leave "Pin 1 Indicator" unconnected during soldering.

Land pattern and soldering recommendations are available at www.st.com/mems.

5 Digital interfaces

The registers embedded inside the LIS33DE may be accessed through both the I^2C and SPI serial interfaces. The latter may be SW configured to operate either in 3-wire or 4-wire interface mode.

The serial interfaces are mapped onto the same pads. To select/exploit the I^2C interface, CS line must be tied high (i.e connected to Vdd_IO).

Table 8. Serial interface pin description

Pin name	Pin description
CS	SPI enable I^2C/SPI mode selection (1: I^2C mode; 0: SPI enabled)
SCL/SPC	I^2C serial clock (SCL) SPI serial port clock (SPC)
SDA/SDI/SDO	I^2C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO)
SDO	SPI serial data output (SDO)

5.1 I^2C serial interface

The LIS33DE I^2C is a bus slave. The I^2C is employed to write data into registers whose content can also be read back.

The relevant I^2C terminology is given in the table below.

Table 9. Serial interface pin description

Term	Description
Transmitter	The device which sends data to the bus
Receiver	The device which receives data from the bus
Master	The device which initiates a transfer, generates clock signals and terminates a transfer
Slave	The device addressed by the master

There are two signals associated with the I^2C bus: the serial clock line (SCL) and the serial DAta line (SDA). The latter is a bidirectional line used for sending and receiving the data to/from the interface. Both the lines are connected to Vdd_IO through a pull-up resistor embedded inside the LIS33DE. When the bus is free both the lines are high.

The I^2C interface is compliant with fast mode (400 KHz) I^2C standards as well as with the normal mode.

5.1.1 I²C operation

The transaction on the bus is started through a START (ST) signal. A START condition is defined as a HIGH to LOW transition on the data line while the SCL line is held HIGH. After this has been transmitted by the master, the bus is considered busy. The next byte of data transmitted after the start condition contains the address of the slave in the first 7 bits and the eighth bit tells whether the Master is receiving data from the slave or transmitting data to the slave. When an address is sent, each device in the system compares the first seven bits after a start condition with its address. If they match, the device considers itself addressed by the Master.

The Slave ADdress (SAD) associated to the LIS33DE is 001110xb. **SDO** pad can be used to modify less significant bit of the device address. If SDO pad is connected to voltage supply LSb is '1' (address 0011101b) else if SDO pad is connected to ground LSb value is '0' (address 0011100b). This solution permits to connect and address two different accelerometers to the same I²C lines.

Data transfer with acknowledge is mandatory. The transmitter must release the SDA line during the acknowledge pulse. The receiver must then pull the data line LOW so that it remains stable low during the HIGH period of the acknowledge clock pulse. A receiver which has been addressed is obliged to generate an acknowledge after each byte of data has been received.

The I²C embedded inside the LIS33DE behaves like a slave device and the following protocol must be adhered to. After the start condition (ST) a slave address is sent, once a slave acknowledge (SAK) has been returned, a 8-bit sub-address is transmitted: the 7 LSb represent the actual register address while the MSB enables address auto increment. If the MSb of the SUB field is 1, the SUB (register address) is automatically incremented to allow multiple data read/write.

The slave address is completed with a Read/Write bit. If the bit is '1' (Read), a repeated START (SR) condition is issued after the two sub-address bytes; if the bit is '0' (Write) the Master will transmit to the slave with direction unchanged.

Table 10. Transfer when Master is writing one byte to slave

Master	ST	SAD + W		SUB		DATA		SP
Slave			SAK		SAK		SAK	

Table 11. Transfer when Master is writing multiple bytes to slave:

Master	ST	SAD + W		SUB		DATA		DATA		SP
Slave			SAK		SAK		SAK		SAK	

Table 12. Transfer when Master is receiving (reading) one byte of data from slave:

Master	ST	SAD + W		SUB		SR	SAD + R			NMAK	SP
Slave			SAK		SAK			SAK	DATA		

Table 13. Transfer when Master is receiving (reading) one byte of data from slave

Master	ST	SAD + W		SUB		SR	SAD + R			NMAK	SP
Slave			SAK		SAK			SAK	DATA		

Table 14. Transfer when Master is receiving (reading) multiple bytes of data from slave

Master	ST	SAD+W		SUB		SR	SAD+R			MAK		MAK		NMAK	SP
Slave			SAK		SAK			SAK	DATA		DATA		DATA		

Data are transmitted in byte format (DATA). Each data transfer contains 8 bits. The number of bytes transferred per transfer is unlimited. Data is transferred with the Most Significant bit (MSb) first. If a receiver can't receive another complete byte of data until it has performed some other function, it can hold the clock line, SCL LOW to force the transmitter into a wait state. Data transfer only continues when the receiver is ready for another byte and releases the data line. If a slave receiver doesn't acknowledge the slave address (i.e. it is not able to receive because it is performing some real time function) the data line must be left HIGH by the slave. The Master can then abort the transfer. A LOW to HIGH transition on the SDA line while the SCL line is HIGH is defined as a STOP condition. Each data transfer must be terminated by the generation of a STOP (SP) condition.

In order to read multiple bytes, it is necessary to assert the most significant bit of the sub-address field. In other words, SUB(7) must be equal to 1 while SUB(6-0) represents the address of first register to be read.

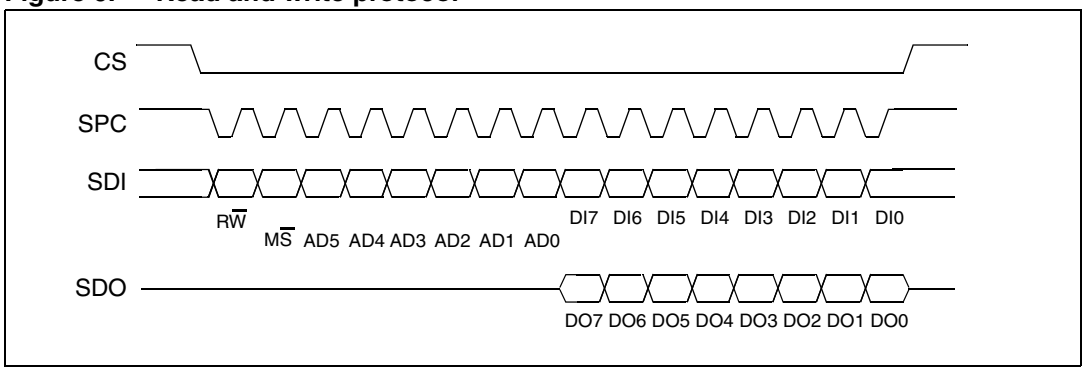
In the presented communication format MAK is master acknowledge and NMAK is No master acknowledge.

5.2 SPI bus interface

The LIS33DE SPI is a bus slave. The SPI allows to write and read the registers of the device.

The Serial Interface interacts with the outside world with 4 wires: **CS**, **SPC**, **SDI** and **SDO**.

Figure 6. Read and write protocol



CS is the Serial Port Enable and it is controlled by the SPI master. It goes low at the start of the transmission and goes back high at the end. **SPC** is the Serial Port Clock and it is controlled by the SPI master. It is stopped high when **CS** is high (no transmission). **SDI** and **SDO** are respectively the Serial Port Data Input and Output. Those lines are driven at the falling edge of **SPC** and should be captured at the rising edge of **SPC**.

Both the read register and write register commands are completed in 16 clock pulses or in multiple of 8 in case of multiple bytes read/write. Bit duration is the time between two falling edges of **SPC**. The first bit (bit 0) starts at the first falling edge of **SPC** after the falling edge

of **CS** while the last bit (bit 15, bit 23, ...) starts at the last falling edge of SPC just before the rising edge of **CS**.

bit 0: R$\overline{W}$ bit. When 0, the data DI(7:0) is written into the device. When 1, the data DO(7:0) from the device is read. In latter case, the chip will drives **SDO** at the start of bit 8.

bit 1: M$\overline{S}$ bit. When 0, the address will remains unchanged in multiple read/write commands. When 1, the address is auto incremented in multiple read/write commands.

bit 2-7: address AD(5:0). This is the address field of the indexed register.

bit 8-15: data DI(7:0) (write mode). This is the data that is written into the device (MSb first).

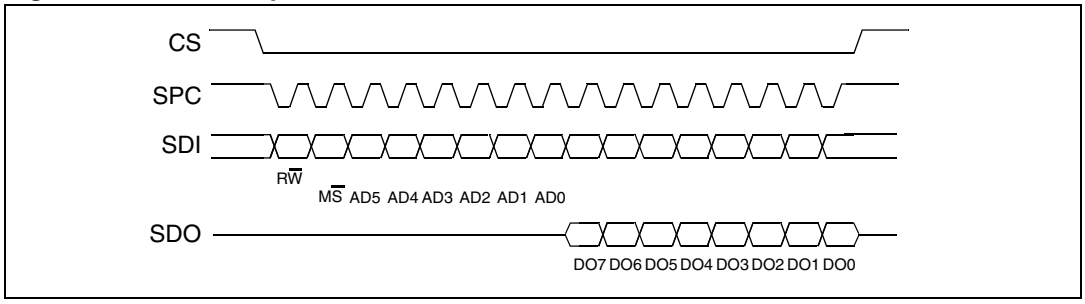
bit 8-15: data DO(7:0) (read mode). This is the data that is read from the device (MSb first).

In multiple read/write commands further blocks of 8 clock periods are added. When M$\overline{S}$ bit is 0 the address used to read/write data remains the same for every block. When M$\overline{S}$ bit is 1 the address used to read/write data is incremented at every block.

The function and the behavior of **SDI** and **SDO** remain unchanged.

5.2.1 SPI read

Figure 7. SPI read protocol



The SPI read command is performed with 16 clock pulses. Multiple byte read command is performed adding blocks of 8 clock pulses at the previous one.

bit 0: READ bit. The value is 1.

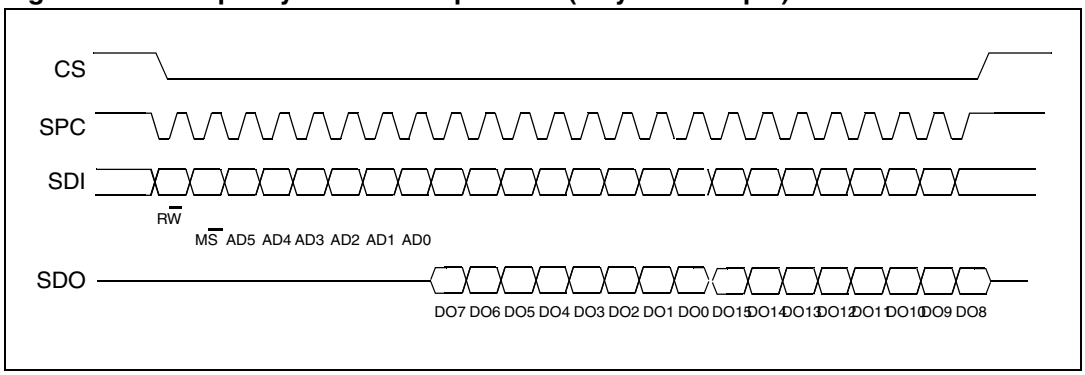
bit 1: M$\overline{S}$ bit. When 0 do not increment address, when 1 increment address in multiple reading.

bit 2-7: address AD(5:0). This is the address field of the indexed register.

bit 8-15: data DO(7:0) (read mode). This is the data that is read from the device (MSb first).

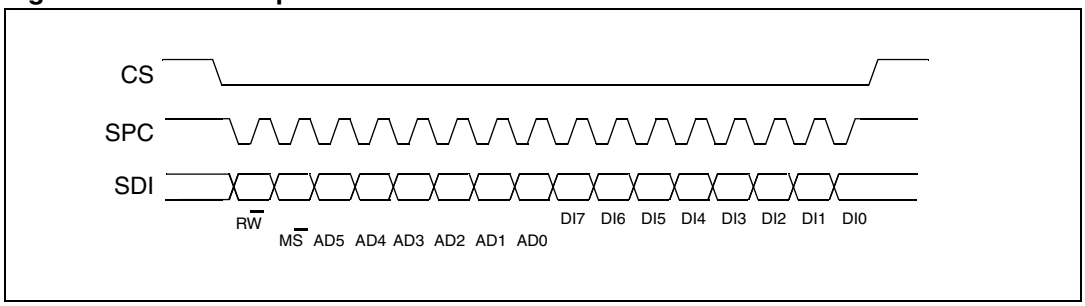
bit 16-... : data DO(...-8). Further data in multiple byte reading.

Figure 8. Multiple bytes SPI read protocol (2 bytes example)



5.2.2 SPI write

Figure 9. SPI write protocol



The SPI Write command is performed with 16 clock pulses. Multiple byte write command is performed adding blocks of 8 clock pulses at the previous one.

bit 0: WRITE bit. The value is 0.

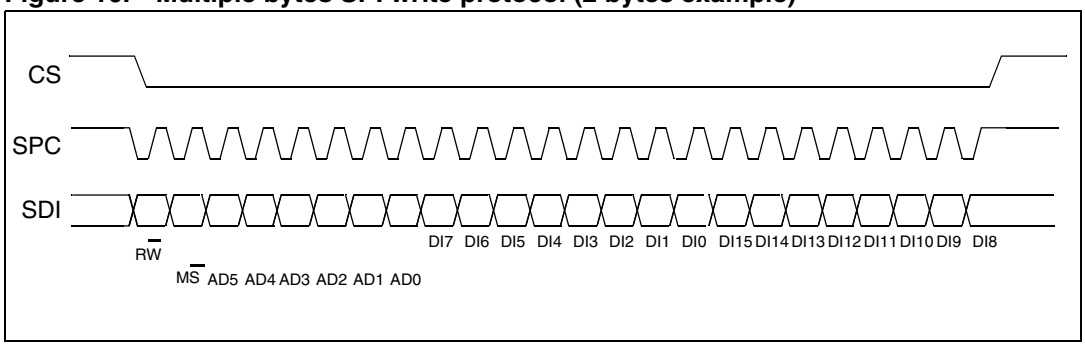
bit 1: MS bit. When 0 do not increment address, when 1 increment address in multiple writing.

bit 2 -7: address AD(5:0). This is the address field of the indexed register.

bit 8-15: data DI(7:0) (write mode). This is the data that is written inside the device (MSb first).

bit 16-... : data DI(...-8). Further data in multiple byte writing.

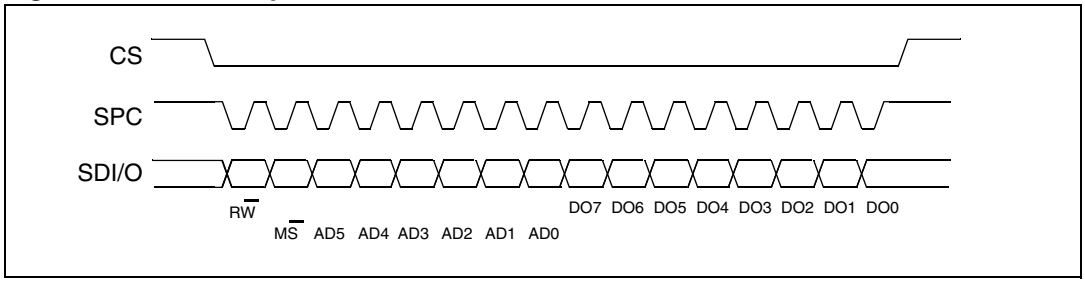
Figure 10. Multiple bytes SPI write protocol (2 bytes example)



5.2.3 SPI read in 3-wires mode

3-wires mode is entered by setting to 1 bit SIM (SPI Serial Interface Mode selection) in CTRL_REG2.

Figure 11. SPI read protocol in 3-wires mode



The SPI read command is performed with 16 clock pulses:

bit 0: READ bit. The value is 1.

bit 1: M$\overline{S}$ bit. When 0 do not increment address, when 1 increment address in multiple reading.

bit 2-7: address AD(5:0). This is the address field of the indexed register.

bit 8-15: data DO(7:0) (read mode). This is the data that is read from the device (MSb first).

Multiple read command is also available in 3-wires mode.

6 Register mapping

The table given below provides a listing of the 8 bit registers embedded in the device and the related address:

Table 15. Register address map

Name	Type	Register address		Default	Comment
		Hex	Binary		
Reserved (do not modify)		00-1F			Reserved
Ctrl_Reg1	rw	20	010 0000	00000111	
Ctrl_Reg2	rw	21	010 0001	00000000	
Ctrl_Reg3	rw	22	010 0010	00000000	
Reserved (do not modify)		23-26			Reserved
Status_Reg	r	27	010 0111	00000000	
--	r	28	010 1000		Not used
OutX	r	29	010 1001	output	
--	r	2A	010 1010		Not used
OutY	r	2B	010 1011	output	
--	r	2C	010 1100		Not used
OutZ	r	2D	010 1101	output	
Reserved (do not modify)		2E-2F			Reserved
FF_WU_CFG	rw	30	011 0000	00000000	
FF_WU_SRC(ack)	r	31	011 0001	00000000	
FF_WU_THS	rw	32	011 0010	00000010	
FF_WU_DURATION	rw	33	011 0011	00000000	
Reserved (do not modify)		34-3F			Reserved

Registers marked as *Reserved* must not be changed. The writing to those registers may cause permanent damages to the device.

The content of the registers that are loaded at boot should not be changed. They contain the factory calibration values. Their content is automatically restored when the device is powered-up.

7 Register description

The device contains a set of registers which are used to control its behavior and to retrieve acceleration data. The registers address, made of 7 bits, is used to identify them and to write the data through serial interface.

7.1 CTRL_REG1 (20h)

Table 16. CTRL_REG1 (20h) register

DR	PD	FS	STP	STM	Zen	Yen	Xen

Table 17. CTRL_REG1 (20h) register description

DR	Data rate selection. Default value: 0 (0: 100 Hz output data rate; 1: 400 Hz output data rate)
PD	Power down control. Default value: 0 (0: power down mode; 1: active mode)
FS	Full scale selection. Default value: 0 (refer to table 2 for typical full scale value)
STP, STM	Self test enable. Default value: 0 (0: normal mode; 1: self test P, M enabled)
Zen	Z axis enable. Default value: 1 (0: Z axis disabled; 1: Z axis enabled)
Yen	Y axis enable. Default value: 1 (0: Y axis disabled; 1: Y axis enabled)
Xen	X axis enable. Default value: 1 (0: X axis disabled; 1: X axis enabled)

DR bit allows to select the data rate at which acceleration samples are produced. The default value is ‘0’ which corresponds to a data-rate of 100 Hz. By changing the content of DR to ‘1’ the selected data-rate will be set equal to 400 Hz.

PD bit allows to turn the device out of power-down mode. The device is in power-down mode when PD= ‘0’ (default value after boot). The device is in normal mode when PD is set to ‘1’.

STP, STM bits are used to activate the self-test function. When the bit is set to one, an output change will occur to the device outputs (refer to Table 2 and 3 for specification) thus allowing to check the functionality of the whole measurement chain.

Zen bit enables the generation of Data Ready signal for Z-axis measurement channel when set to ‘1’. The default value is ‘1’.

Yen bit enables the generation of Data Ready signal for Y-axis measurement channel when set to ’1’. The default value is ’1’.

Xen bit enables the generation of Data Ready signal for X-axis measurement channel when set to ’1’. The default value is ’1’.

7.2 CTRL_REG2 (21h)

Table 18. CTRL_REG2 (21h) register

SIM	BOOT	0(1)	0(1)	0(1)	0(1)	0(1)	0(1)

1. Bit to be kept to “0” for correct device functionality.

Table 19. CTRL_REG2 (21h) register description

SIM	SPI serial interface mode selection. Default value: 0 (0: 4-wire interface; 1: 3-wire interface)
BOOT	Reboot memory content. Default value: 0 (0: normal mode; 1: reboot memory content)

SIM bit selects the SPI serial interface mode. When SIM is ‘0’ (default value) the 4-wire interface mode is selected. The data coming from the device are sent to SDO pad. In 3-wire interface mode output data are sent to SDA_SDI pad.

BOOT bit is used to refresh the content of internal registers stored in the flash memory block. At the device power up the content of the flash memory block is transferred to the internal registers related to trimming functions to permit a good behavior of the device itself. If for any reason the content of trimming registers is changed it is sufficient to use this bit to restore correct values. When BOOT bit is set to ‘1’ the content of internal flash is copied inside corresponding internal registers and it is used to calibrate the device. These values are factory trimmed and they are different for every accelerometer. They permit a good behavior of the device and normally they have not to be changed. At the end of the boot process the BOOT bit is set again to ‘0’.

7.3 CTRL_REG3 [Interrupt CTRL register] (22h)

Table 20. CTRL_REG3 (22h) register

IHL	0(1)	0(2)	0(2)	0(2)	ICFG2	ICFG1	ICFG0

1. Bit to be kept to “0” for correct push-pull on Interrupt pad (INT).
2. Bit to be kept to “0” for correct device functionality.

Table 21. CTRL_REG3 (22h) register description

IHL	Interrupt active high, low. Default value 0. (0: active high; 1: active low)
ICFG2- ICFG0	Data signal on INT pad control bits. Default value 000. (see table below)

Table 22. Data signal on INT pad control bits

ICFG2(1)	ICFG1(1)	ICFG0(1)	INT pad
0	0	0	GND
0	0	1	FF_WU
1	0	0	Data ready

1. These are the allowed bit configurations. Each other configuration may cause incorrect device functionality.

7.4 STATUS_REG (27h)

Table 23. STATUS_REG (27h) register

ZXYOR	ZOR	YOR	XOR	ZYXDA	ZDA	YDA	XDA

Table 24. STATUS_REG (27h) register description

ZYXOR	X, Y and Z axis data overrun. Default value: 0 (0: no overrun has occurred; 1: new data has overwritten the previous one before it is read)
ZOR	Z axis data overrun. Default value: 0 (0: no overrun has occurred; 1: a new data for the Z-axis has overwritten the previous one)
YOR	Y axis data overrun. Default value: 0 (0: no overrun has occurred; 1: a new data for the Y-axis has overwritten the previous one)
XOR	X axis data overrun. Default value: 0 (0: no overrun has occurred; 1: a new data for the X-axis has overwritten the previous one)
ZYXDA	X, Y and Z axis new data available. Default value: 0 (0: a new set of data is not yet available; 1: a new set of data is available)
ZDA	Z axis new data available. Default value: 0 (0: a new data for the Z-axis is not yet available; 1: a new data for the Z-axis is available)
YDA	Y axis new data available. Default value: 0 (0: a new data for the Y-axis is not yet available; 1: a new data for the Y-axis is available)
XDA	X axis new data available. Default value: 0 (0: a new data for the X-axis is not yet available; 1: a new data for the X-axis is available)

7.5 OUT_X (29h)

Table 25. OUT_X (29h) register

XD7	XD6	XD5	XD4	XD3	XD2	XD1	XD0

X axis output data expressed as 2's complement number.

7.6 OUT_Y (2Bh)

Table 26. OUT_Y (2Bh) register

YD7	YD6	YD5	YD4	YD3	YD2	YD1	YD0

Y axis output data expressed as 2's complement number.

7.7 OUT_Z (2Dh)

Table 27. OUT_Z (2Dh) register

ZD7	ZD6	ZD5	ZD4	ZD3	ZD2	ZD1	ZD0

Z axis output data expressed as 2's complement number.

7.8 FF_WU_CFG (30h)

Table 28. FF_WU_CFG (30h) register

AOI	LIR	ZHIE	ZLIE	YHIE	YLIE	XHIE	XLIE

Table 29. FF_WU_CFG (30h) register description

AOI	And/or combination of interrupt events. Default value: 0 (0: OR combination of interrupt events; 1: AND combination of interrupt events)
LIR	Latch Interrupt request into FF_WU_SRC reg with the FF_WU_SRC reg cleared by reading FF_WU_SRC reg. Default value: 0 (0: interrupt request not latched; 1: interrupt request latched)
ZHIE	Enable interrupt generation on Z high event. Default value: 0 (0: disable interrupt request; 1: enable interrupt request on measured accel. value higher than preset threshold)
ZLIE	Enable interrupt generation on Z low event. Default value: 0 (0: disable interrupt request; 1: enable interrupt request on measured accel. value lower than preset threshold)

Table 29. FF_WU_CFG (30h) register description (continued)

YHIE	Enable interrupt generation on Y high event. Default value: 0 (0: disable interrupt request; 1: enable interrupt request on measured accel. value higher than preset threshold)
YLIE	Enable interrupt generation on Y low event. Default value: 0 (0: disable interrupt request; 1: enable interrupt request on measured accel. value lower than preset threshold)
XHIE	Enable interrupt generation on X high event. Default value: 0 (0: disable interrupt request; 1: enable interrupt request on measured accel. value higher than preset threshold)
XLIE	Enable interrupt generation on X low event. Default value: 0 (0: disable interrupt request; 1: enable interrupt request on measured accel. value lower than preset threshold)

7.9 FF_WU_SRC (31h)

Table 30. FF_WU_SRC (31h) register

--	IA	ZH	ZL	YH	YL	XH	XL

Table 31. FF_WU_SRC (31h) register description

IA	Interrupt active. Default value: 0 (0: no interrupt has been generated; 1: one or more interrupts have been generated)
ZH	Z high. Default value: 0 (0: no interrupt, 1: ZH event has occurred)
ZL	Z low. Default value: 0 (0: no interrupt; 1: ZL event has occurred)
YH	Y high. Default value: 0 (0: no interrupt, 1: YH event has occurred)
YL	Y Low. Default value: 0 (0: no interrupt, 1: YL event has occurred)
XH	X high. Default value: 0 (0: no interrupt, 1: XH event has occurred)
XL	X low. Default value: 0 (0: no interrupt, 1: XL event has occurred)

Free-fall and wake-up source register. Read only register.

Reading at this address clears FF_WU_SRC register and the FF, WU interrupt and allows the refreshment of data in the FF_WU_SRC register if the latched option is chosen.

7.10 FF_WU_THS (32h)

Table 32. FF_WU_THS (32h) register

DCRM	THS6	THS5	THS4	THS3	THS2	THS1	THS0

Table 33. FF_WU_THS (32h) register description

DCRM	Resetting mode selection. Default value: 0 (0: counter reset; 1: counter decremented)
THS6, THS0	Free-fall / wake-up Threshold: default value: 000 0010

Most significant bit (DCRM) is used to select the resetting mode of the duration counter. If DCRM=0 counter is reset when the interrupt is no more active else if DCRM=1 duration counter is decremented.

7.11 FF_WU_DURATION (33h)

Table 34. FF_WU_DURATION (33h) register

D7	D6	D5	D4	D3	D2	D1	D0

Table 35. FF_WU_DURATION (33h) register description

D7-D0	Duration value. Default value: 0000 0000

Duration register for free-fall/wake-up interrupt. Duration step and maximum value depend on the ODR chosen. Step 2.5 msec, from 0 to 637.5 msec if ODR=400 Hz, else step 10 msec, from 0 to 2.55 sec when ODR=100 Hz. The counter used to implement duration function is blocked when LIR=1 in configuration register and the interrupt event is verified.

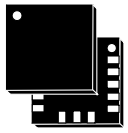
8 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

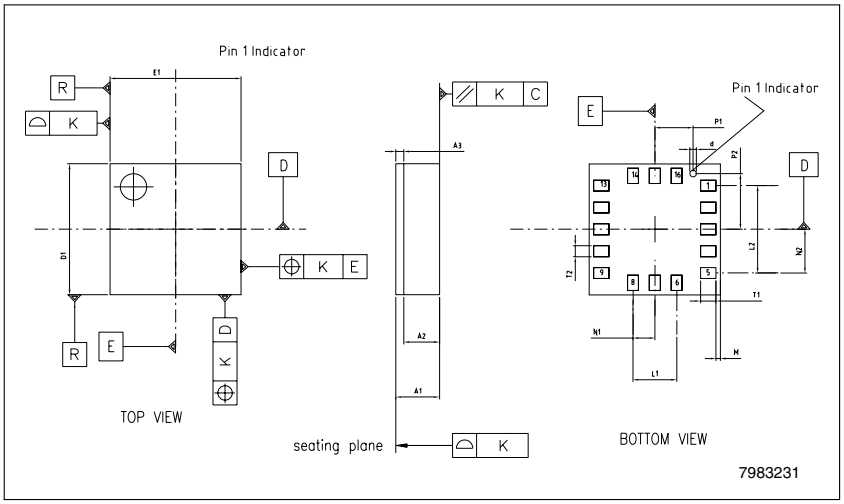
Figure 12. LGA 16: mechanical data and package dimensions

Dimensions						
Ref.	mm			inch		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A1			1.000			0.0394
A2		0.785			0.0309	
A3		0.200			0.0079	
D1	2.850	3.000	3.150	0.1122	0.1181	0.1240
E1	2.850	3.000	3.150	0.1122	0.1181	0.1240
L1		1.000	1.060		0.0394	0.0417
L2		2.000	2.060		0.0787	0.0811
N1		0.500			0.0197	
N2		1.000			0.0394	
M	0.040	0.100	0.160	0.0016	0.0039	0.0063
P1		0.875			0.0344	
P2		1.275			0.0502	
T1	0.290	0.350	0.410	0.0114	0.0138	0.0161
T2	0.190	0.250	0.310	0.0075	0.0098	0.0122
d		0.150			0.0059	
k		0.050			0.0020	

Outline and mechanical data



LGA16 (3x3x1.0mm)
Land Grid Array Package



9 Revision history

Table 36. Document revision history

Date	Revision	Changes
17-Apr-2009	1	Initial release

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST’s terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST’S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER’S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com